

Notice of References Cited	Application/Control No. 10/591,475		Applicant(s)/Patent Under Reexamination TAKASHIMA ET AL.	
	Examiner Mark L. Shevin		Art Unit 1793	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0179207	12-2002	Koike et al.	148/648
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N	JP 2000-337,333	12-2000	Japan	Ibaraki et al	F16B 35/00
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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